

## DATA SHEET

Model BRFS100

Test

EMI

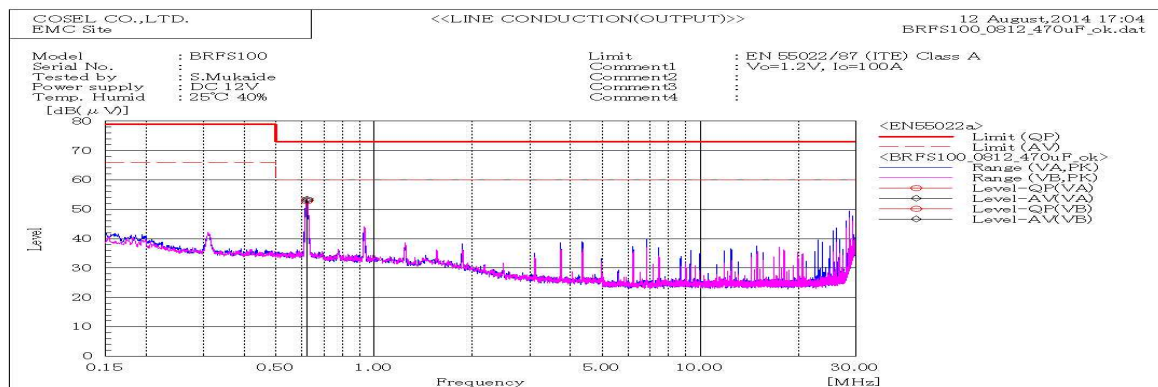
Line conduction & Radiated emission

Date 12-Aug-14

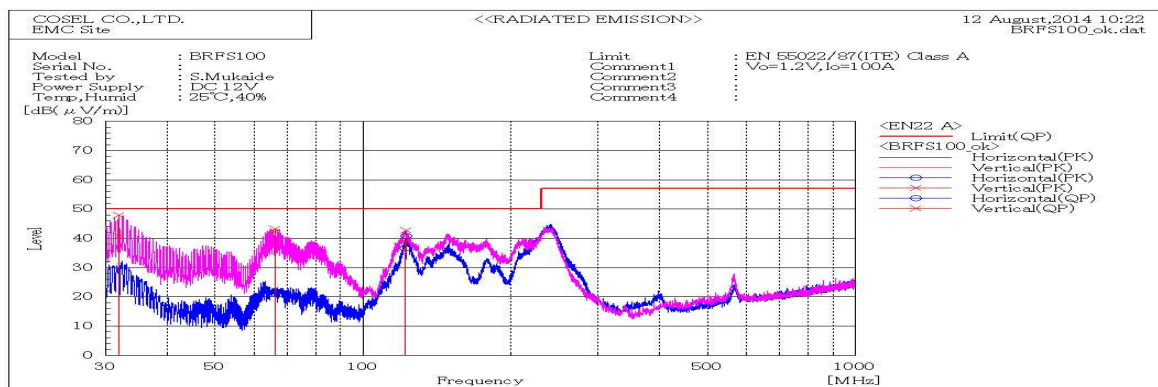
Temp. 25 degreeC

Humid. 40 %RH

Tested by S.Mukaide



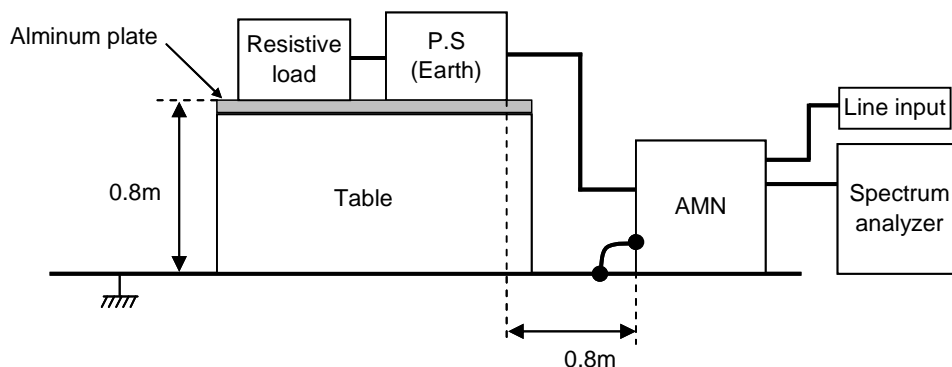
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.6235	VA	33.2	33.4	20.1	53.3	53.5	73	60	19.7	6.5	Pass
0.6238	VB	32.7	32.9	20.1	52.8	53	73	60	20.2	7	Pass



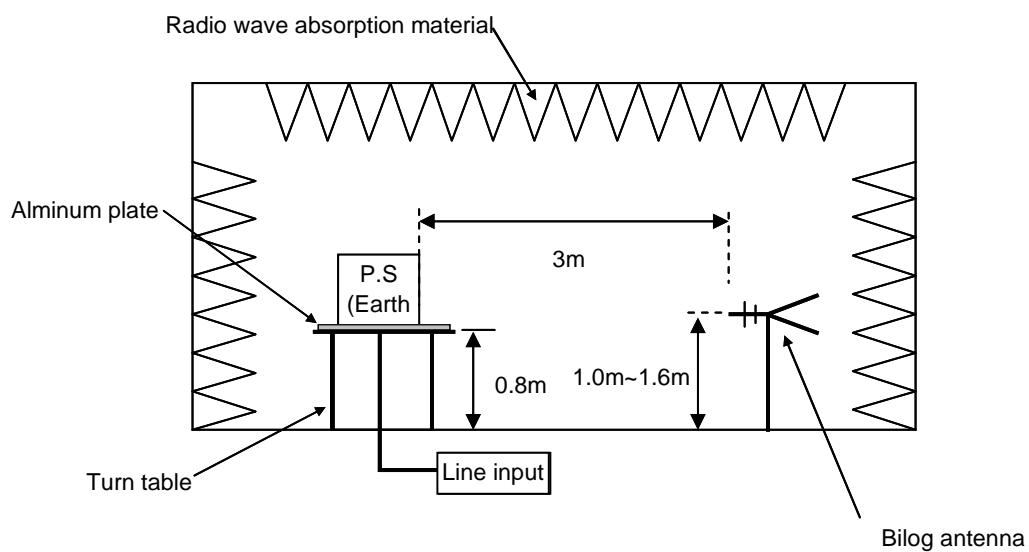
Frequency MHz	Polariz ation	Stabili ty	Readin g dB(μV)	Space Loss dB	Level dB(m W)	Limit dB(m W)	Margin dB	Pass/ Fail	Height cm	Angle deg
			QP		QP	QP				
31.855	V	Stable	54.8	-14	40.8	50	9.2	Pass	101	162
66.186	V	Stable	64	-21.7	42.3	50	7.7	Pass	124	121
121.862	H	Stable	55.9	-19.3	36.6	50	13.4	Pass	136	114
121.757	V	Stable	55.9	-16.9	39	50	11	Pass	102	24

DATA SHEET		Date	12-Aug-14
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide

## 1. Line conduction



## 2. Radiated emission

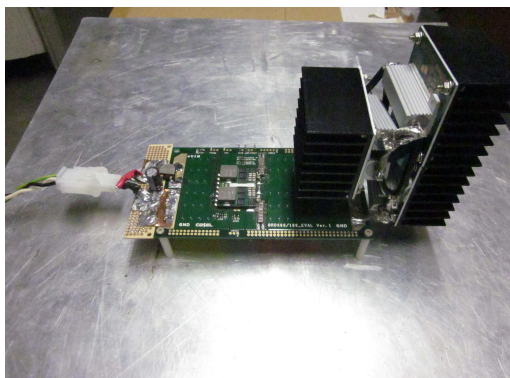


## Conditions

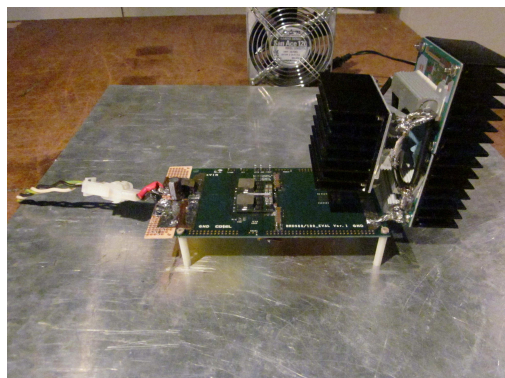
Test : EMI  
Model Name : BRFS100

○Photographs of Test Set-Up

### LINE CONDUCTION

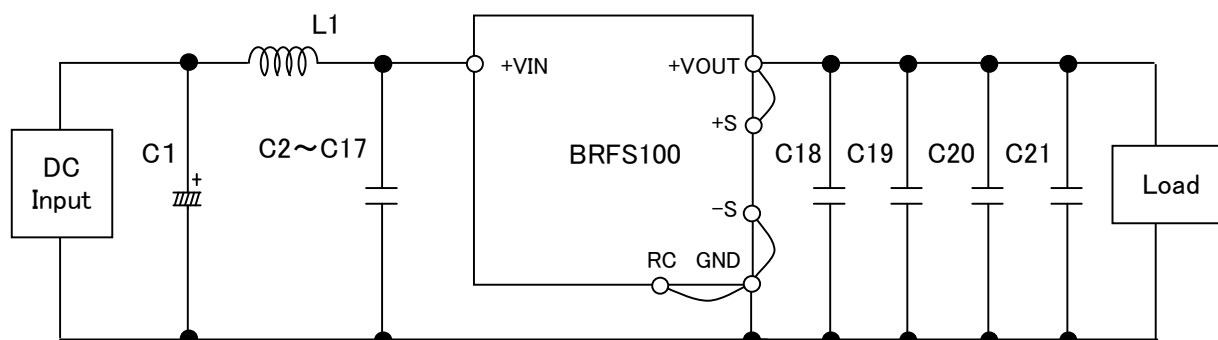


### RADIATED EMISSION



○Testing circuitry

○Test Circuit



C1	: 25V	470 $\mu$ F	Electrolytic capacitor
C2~C17	: 16V	22 $\mu$ F	Ceramic capacitor
C18~C21	: 6.3V	100 $\mu$ F	Ceramic capacitor
L1	: 0.3 $\mu$ H	ETQP2H0R3BFA	(Panasonic Electronics Devices)